UNISONIC TECHNOLOGIES CO., LTD

1NM60-Q **Power MOSFET**

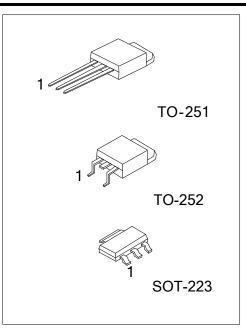
1.0A, 600V N-CHANNEL SUPER-JUNCTION MOSFET

DESCRIPTION

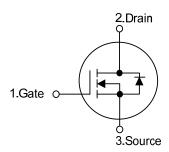
The UTC 1NM60-Q is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at DC-DC, AC-DC converters for power applications.

FEATURES

- * $R_{DS(ON)}$ < 4.60 @ V_{GS} = 10V, I_{D} =0.5A
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness



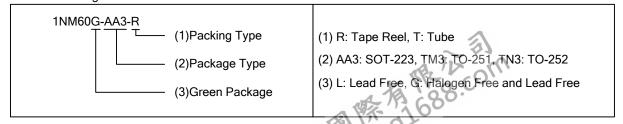
SYMBOL



ORDERING INFORMATION

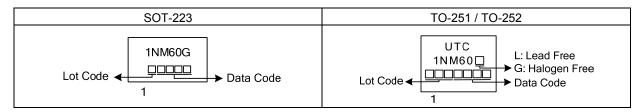
Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
-	1NM60G-AA3-R	SOT-223	G	D	S	Tape Reel	
1NM60L-TM3-T	1NM60G-TM3-T	TO-251	G	D	S	Tube	
1NM60L-TN3-R	1NM60G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



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MARKING



■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	600	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous	I_{D}	1.0	Α	
	Pulsed (Note 2)	I_{DM}	4.0	Α	
Avalanche Current (Note 2)		I_{AR}	1.3	Α	
Avalanche Energy	ne Energy Single Pulsed (Note 3)		8.5	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	5.5	V/ns	
Power Dissipation	SOT-223	ם	8.0	W	
	TO-251/TO-252	P_{D}	28	W	
Junction Temperature		T_J	+150	°C	
Storage Temperature		T_{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=10mH, I_{AS} =1.3A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} = 25°C
- 4. $I_{SD} \le 1.0A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C

■ THERMAL CHARACTERISTICS

PARAMETER		SYMBOL	SYMBOL RATINGS	
Junction to Ambient	SOT-223	Q	150	°C/W
	TO-251/TO-252	θ_{JA}	110	°C/W
Junction to Case	SOT-223	Q	15.6	°C/W
	TO-251/TO-252	θ_{JC}	4.46	°C/W



ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

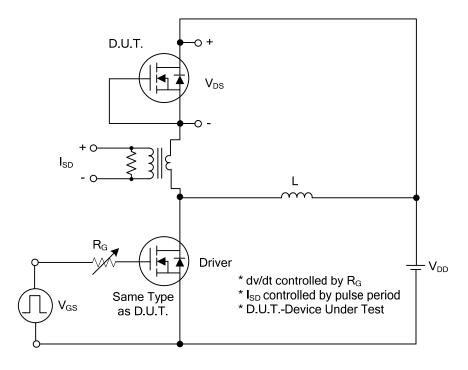
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	600			V
Drain-Source Leakage Current		I _{DSS}	$V_{DS} = 600V, V_{GS} = 0V$			10	μΑ
Gate-Source Leakage Current	Forward	I _{GSS}	$V_{GS} = +30V, V_{DS} = 0V$			+100	nA
	Reverse		$V_{GS} = -30V, V_{DS} = 0V$			-100	nA
ON CHARACTERISTICS							
Gate Threold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$			4.5	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_D = 0.5A$			4.6	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance	nput Capacitance				83		pF
Output Capacitance		C_{OSS}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		62		pF
Reverse Transfer Capacitance		C_{RSS}			8.0		pF
SWITCHING CHARACTERISTIC	S			-		-	
Total Gate Charge (Note 1)		Q_G	\/ -50\/ \/ -10\/ -0.5A		19		nC
Gate to Source Charge		Q_GS	V_{DS} =50V, V_{GS} =10V, I_{D} =0.5A I_{G} =100µA (Note 1, 2)		1.8		nC
Gate to Drain Charge		Q_GD	IG-100μΑ (Note 1, 2)		2.6		nC
Turn-ON Delay Time (Note 1)		t _{D (ON)}			43		ns
Rise Time		t_R	V_{DD} =30V, V_{GS} =10V, I_{D} =0.5A,		36		ns
Turn-OFF Delay Time		$t_{D(OFF)}$	R _G =25Ω (Note 1, 2)		59		ns
Fall-Time	Fall-Time				25		ns
SOURCE- DRAIN DIODE RATIN	GS AND CHA	ARACTERISTI	cs			ā.	
Maximum Body-Diode Continuous Current		I _S				1.0	Α
Maximum Body-Diode Pulsed Current		I _{SM}				4.0	Α
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I _S =1.0A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time (Note 1)		t _{rr}	I _S =1.0A, V _{GS} =0V,		160		nS
Body Diode Reverse Recovery Charge		Qrr	dI _F /dt=100A/μs		0.5		μC

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle≤2%.

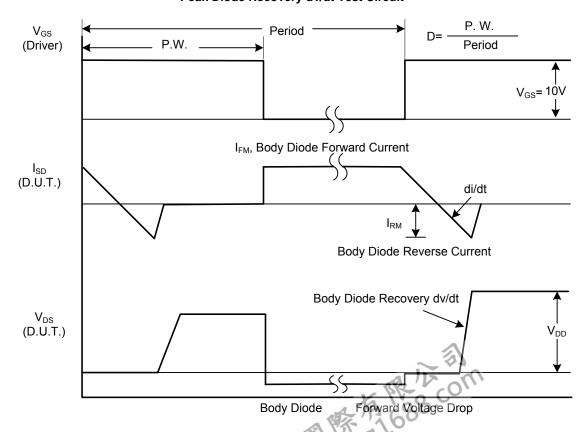


^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

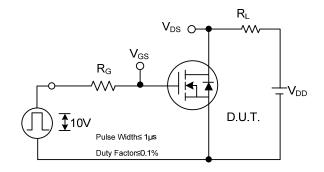


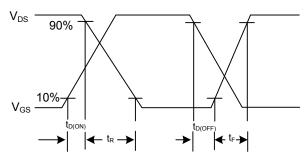
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

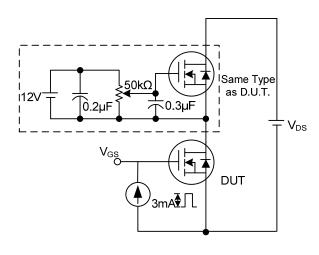
TEST CIRCUITS AND WAVEFORMS (Cont.)

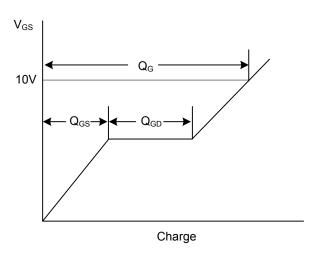




Switching Test Circuit

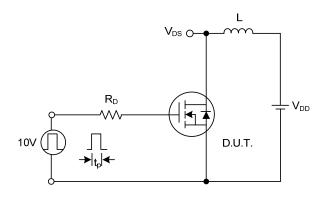
Switching Waveforms

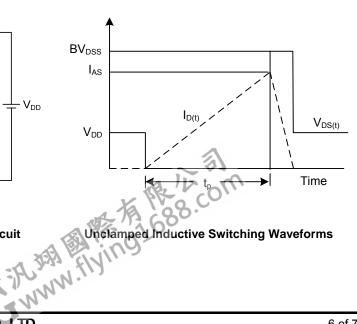




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

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